



12-BIT, 2 ANALOG INPUT, 8 MSPS, SIMULTANEOUS SAMPLING ANALOG-TO-DIGITAL CONVERTER

FEATURES

- Simultaneous Sampling of 2 Single-Ended Signals or 1 Differential Signal
- Signal-to-Noise Ratio: 68 dB at $f_1 = 2$ MHz
- Differential Nonlinearity Error: ± 1 LSB
- Integral Nonlinearity Error: ± 1.5 LSB
- Auto-Scan Mode for 2 Inputs
- 3-V or 5-V Digital Interface Compatible
- Low Power: 218 mW Max at 5 V
- Power Down: 1 mW Max
- 5-V Analog Single Supply Operation
- Internal Voltage References . . . 50 PPM/°C and $\pm 5\%$ Accuracy
- Glueless DSP Interface
- Parallel μ C/DSP Interface

APPLICATIONS

- Radar Applications
- Communications
- Control Applications
- High-Speed DSP Front-End
- Automotive Applications

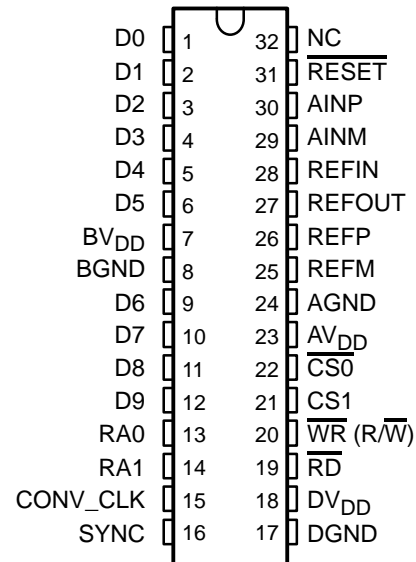
DESCRIPTION

The THS1209 is a CMOS, low-power, 12-bit, 8 MSPS analog-to-digital converter (ADC). The speed, resolution, bandwidth, and single-supply operation are suited for applications in radar, imaging, high-speed acquisition, and communications. A multistage pipelined architecture with output error correction logic provides for no missing codes over the full operating temperature range. Internal control registers allow for programming the ADC into the desired mode. The

THS1209 consists of two analog inputs, which are sampled simultaneously. These inputs can be selected individually and configured to single-ended or differential inputs. Internal reference voltages for the ADC (1.5 V and 3.5 V) are provided. An external reference can also be chosen to suit the dc accuracy and temperature drift requirements of the application.

The THS1209C is characterized for operation from 0°C to 70°C, and the THS1209I is characterized for operation from –40°C to 85°C.

DA PACKAGE
(TOP VIEW)



ORDERING INFORMATION

| T _A | PACKAGED DEVICE |
|----------------|-----------------|
| | TSSOP (A) |
| 0°C to 70°C | THS1209CDA |
| –40°C to 85°C | THS1209IDA |



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted⁽¹⁾

| | | UNITS |
|--|--------------------------|--|
| Supply voltage range | DGND to DV _{DD} | –0.3 V to 8.5 V |
| | BGND to BV _{DD} | –0.3 V to 8.5 V |
| | AGND to AV _{DD} | –0.3 V to 8.5 V |
| Analog input voltage range | | AGND –0.3 V to AV _{DD} + 1.5 V |
| Reference input voltage | | –0.3 V + AGND to AV _{DD} + 0.3 V |
| Digital input voltage range | | –0.3 V to BV _{DD} /DV _{DD} + 0.3 V |
| Operating virtual junction temperature range, T _J | | –40°C to 150°C |
| Operating free-air temperature range, T _A | THS1209C | 0°C to 70°C |
| | THS1209I | –40°C to 85°C |
| Storage temperature range, T _{stg} | | –65°C to 150°C |
| Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds | | 260°C |

(1) Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

| POWER SUPPLY | | MIN | NOM | MAX | UNIT |
|----------------|------------------|------|-----|------|------|
| Supply voltage | AV _{DD} | 4.75 | 5 | 5.25 | V |
| | DV _{DD} | 4.75 | 5 | 5.25 | |
| | BV _{DD} | 3 | | 5.25 | |

| ANALOG AND REFERENCE INPUTS | | MIN | NOM | MAX | UNIT |
|---|--|-------------------|-----|-----------------------|------|
| Analog input voltage in single-ended configuration | | V _{REFM} | | V _{REFP} | V |
| Common-mode input voltage V _{CM} in differential configuration | | 1 | 2.5 | 4 | V |
| External reference voltage, V _{REFP} (optional) | | | 3.5 | AV _{DD} –1.2 | V |
| External reference voltage, V _{REFM} (optional) | | 1.4 | 1.5 | | V |
| Input voltage difference, REFP – REFM | | | 2 | | V |

| DIGITAL INPUTS | | MIN | NOM | MAX | UNIT |
|---|---------------------------|-----|-----|------|------|
| High-level input voltage, V _{IH} | BV _{DD} = 3.3 V | 2 | | | V |
| | BV _{DD} = 5.25 V | 2.8 | | | V |
| Low-level input voltage, V _{IL} | BV _{DD} = 3.3 V | | | 0.8 | V |
| | BV _{DD} = 5.25 V | | | 0.8 | V |
| Input CONV_CLK frequency | | | | 8 | MHz |
| CONV_CLK pulse duration, clock high, t _w (CONV_CLKH) | | | 62 | 5000 | ns |
| CONV_CLK pulse duration, clock low, t _w (CONV_CLKL) | | | 62 | 5000 | ns |
| Operating free-air temperature, T _A | THS1209CDA | 0 | | 70 | °C |
| | THS1209IDA | –40 | | 85 | |

ELECTRICAL CHARACTERISTICS

 over recommended operating conditions, $AV_{DD} = DV_{DD} = 5\text{ V}$, $BV_{DD} = 3.3\text{ V}$, $V_{REF} = \text{internal}$ (unless otherwise noted)

| DIGITAL SPECIFICATIONS | | | | | | |
|------------------------|-------------------------------------|--|---------------|-----|-----|---------------|
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
| Digital inputs | | | | | | |
| I_{IH} | High-level input current | $DV_{DD} = \text{digital inputs}$ | -50 | | 50 | μA |
| I_{IL} | Low-level input current | Digital input = 0 V | -50 | | 50 | μA |
| C_i | Input capacitance | | | 5 | | pF |
| Digital outputs | | | | | | |
| V_{OH} | High-level output voltage | $I_{OH} = -50\ \mu\text{A}$, $BV_{DD} = 3.3\text{ V}, 5\text{ V}$ | $BV_{DD}-0.5$ | | | V |
| V_{OL} | Low-level output voltage | $I_{OL} = 50\ \mu\text{A}$, $BV_{DD} = 3.3\text{ V}, 5\text{ V}$ | | | 0.4 | V |
| I_{OZ} | High-impedance-state output current | $CS1 = \text{DGND}$, $CS0 = DV_{DD}$ | -10 | | 10 | μA |
| C_O | Output capacitance | | | 5 | | pF |
| C_L | Load capacitance at databus D0 – D9 | | | | 30 | pF |

ELECTRICAL CHARACTERISTICS

 over recommended operating conditions, $AV_{DD} = DV_{DD} = 5\text{ V}$, $BV_{DD} = 3.3\text{ V}$, $f_s = 8\text{ MSPS}$, $V_{REF} = \text{internal}$ (unless otherwise noted)

| DC SPECIFICATIONS | | | | | | |
|--|------------------------|---|-------|------|-----------|-------------------------|
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
| Resolution | | | 12 | | | Bits |
| Accuracy | | | | | | |
| Integral nonlinearity, INL | | | | | ± 1.5 | LSB |
| Differential nonlinearity, DNL | | | | | ± 1 | LSB |
| Offset error | | After calibration in single-ended mode | | 20 | | LSB |
| | | After calibration in differential mode | -20 | | 20 | LSB |
| Gain error | | | -20 | | 20 | LSB |
| Analog input | | | | | | |
| Input capacitance | | | | 15 | | pF |
| Input leakage current | | $V_{AIN} = V_{REFM}$ to V_{REFP} | | | ± 10 | μA |
| Internal voltage reference | | | | | | |
| Accuracy, V_{REFP} | | | 3.3 | 3.5 | 3.7 | V |
| Accuracy, V_{REFM} | | | 1.4 | 1.5 | 1.6 | V |
| Temperature coefficient | | | | 50 | | PPM/ $^{\circ}\text{C}$ |
| Reference noise | | | | 100 | | μV |
| Accuracy, REFOUT | | | 2.475 | 2.5 | 2.525 | V |
| Power supply | | | | | | |
| I_{DDA} | Analog supply current | $AV_{DD} = DV_{DD} = 5\text{ V}$, $BV_{DD} = 3.3\text{ V}$ | | 38 | 40 | mA |
| I_{DDD} | Digital supply current | $AV_{DD} = DV_{DD} = 5\text{ V}$, $BV_{DD} = 3.3\text{ V}$ | | 0.5 | 1 | mA |
| I_{DDB} | Buffer supply current | $AV_{DD} = DV_{DD} = 5\text{ V}$, $BV_{DD} = 3.3\text{ V}$ | | 1.5 | 4 | mA |
| Power dissipation | | $AV_{DD} = DV_{DD} = 5\text{ V}$, $BV_{DD} = 3.3\text{ V}$ | | 188 | 218 | mW |
| Power dissipation in power down with conversion clock inactive | | $AV_{DD} = DV_{DD} = 5\text{ V}$, $BV_{DD} = 3.3\text{ V}$ | | 0.25 | | mW |

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ELECTRICAL CHARACTERISTICS

 over recommended operating conditions, V_{REF} = internal, $f_s = 8$ MSPS, $f_l = 2$ MHz at -1 dBFS (unless otherwise noted)

| AC SPECIFICATIONS, $AV_{DD} = DV_{DD} = 5$ V, $BV_{DD} = 3.3$ V, $C_L < 30$ pF | | | | | | |
|--|---|------------------------------|-------|------|-----|------|
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
| SINAD | Signal-to-noise ratio + distortion | Differential mode | 63 | 65 | | dB |
| | | Single-ended mode | 62 | 64 | | dB |
| SNR | Signal-to-noise ratio | Differential mode | 64 | 69 | | dB |
| | | Single-ended mode | 64 | 68 | | dB |
| THD | Total harmonic distortion | Differential mode | | -70 | -67 | dB |
| | | Single-ended mode | | -68 | -64 | dB |
| ENOB (SNR) | Effective number of bits | Differential mode | 10.17 | 10.5 | | Bits |
| | | Single-ended mode | 10 | 10.3 | | Bits |
| SFDR | Spurious free dynamic range | Differential mode | 67 | 71 | | dB |
| | | Single-ended mode | 65 | 69 | | dB |
| Analog Input | | | | | | |
| | Full-power bandwidth with a source impedance of 150 Ω in differential configuration. | Full scale sinewave, -3 dB | | 98 | | MHz |
| | Full-power bandwidth with a source impedance of 150 Ω in single-ended configuration. | Full scale sinewave, -3 dB | | 54 | | MHz |
| | Small-signal bandwidth with a source impedance of 150 Ω in differential configuration. | 100 mVpp sinewave, -3 dB | | 98 | | MHz |
| | Small-signal bandwidth with a source impedance of 150 Ω in single-ended configuration. | 100 mVpp sinewave, -3 dB | | 54 | | MHz |

TIMING REQUIREMENTS

 $AV_{DD} = DV_{DD} = 5$ V, $BV_{DD} = 3.3$ V, V_{REF} = internal, $C_L < 30$ pF

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------------------|--|-----------------|-----|-----|-----|-------------|
| t_{pipe} | Latency | | | 5 | | CONV CLK |
| $t_{su}(CONV_CLKL-READL)$ | Setup time, CONV_CLK low before CS valid | | 10 | | | ns |
| $t_{su}(READH-CONV_CLKL)$ | Setup time, CS invalid to CONV_CLK low | | 20 | | | ns |
| $t_d(CONV_CLKL-SYNCL)$ | Delay time, CONV_CLK low to SYNC low | | | | 10 | ns |
| $t_d(CONV_CLKL-SYNCH)$ | Delay time, CONV_CLK low to SYNC high | | | | 10 | ns |

Terminal Functions

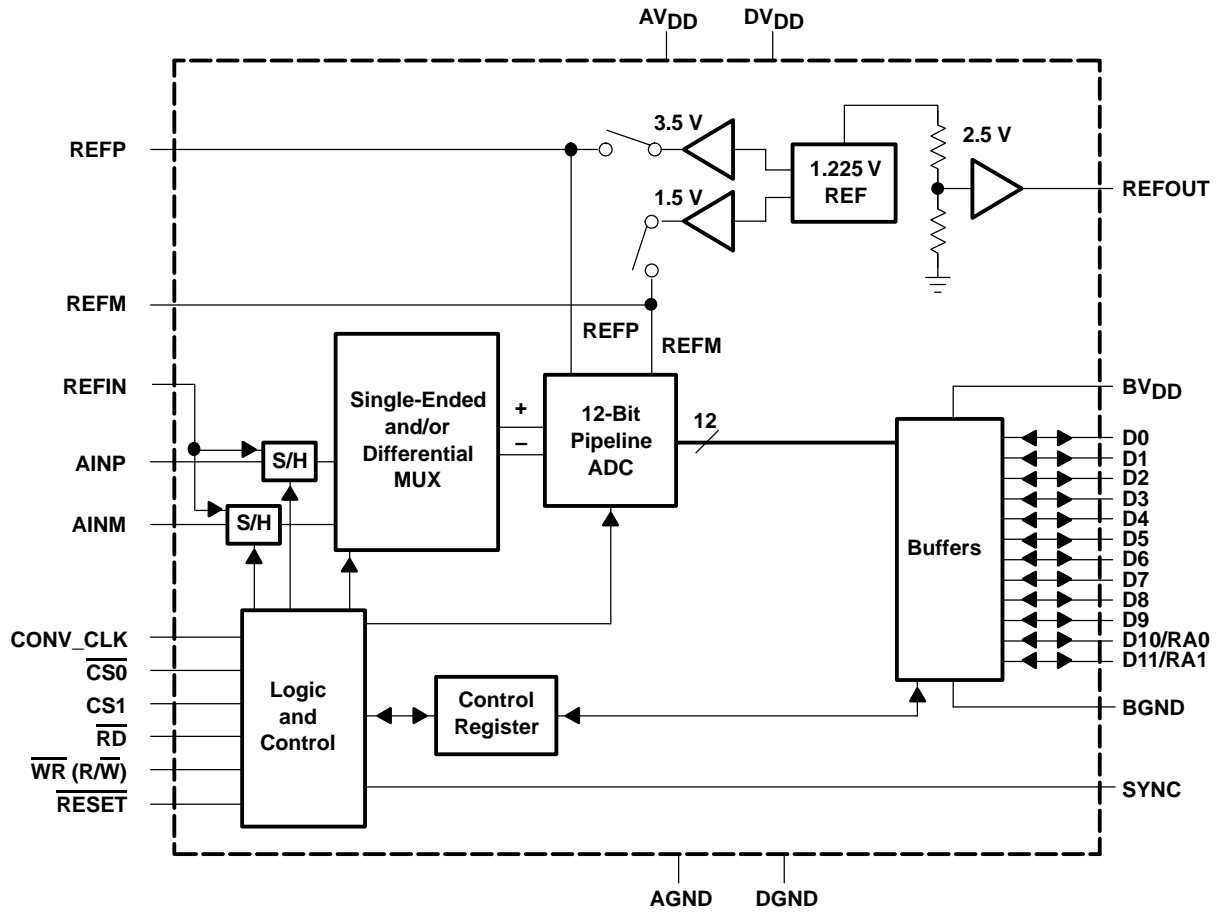
| TERMINAL NAME NO. | | I/O | DESCRIPTION |
|---|--------------|-------|---|
| AINP | 30 | I | Analog input, single-ended or positive input of differential channel A |
| AINM | 29 | I | Analog input, single-ended or negative input of differential channel A |
| AVDD | 23 | I | Analog supply voltage |
| AGND | 24 | I | Analog ground |
| BVDD | 7 | I | Digital supply voltage for buffer |
| BGND | 8 | I | Digital ground for buffer |
| CONV_CLK | 15 | I | Digital input. This input is the conversion clock input |
| $\overline{\text{CS0}}$ | 22 | I | Chip select input (active low) |
| CS1 | 21 | I | Chip select input (active high) |
| SYNC | 16 | O | Synchronization output. This signal indicates in a multi-channel operation that data of channel A is brought to the digital output and can therefore be used for synchronization. |
| DGND | 17 | I | Digital ground. Ground reference for digital circuitry. |
| DVDD | 18 | I | Digital supply voltage |
| D0 – D9 | 1–6, 9–12 | I/O/Z | Digital input, output; D0 = LSB |
| RA0/D10 | 13 | I/O/Z | Digital input, output. The data line D10 is also used as an address line (RA0) for the control register. This is required for writing to control register 0 and control register 1. See Table 7. |
| RA1/D11 | 14 | I/O/Z | Digital input, output (D11 = MSB). The data line D11 is also used as an address line (RA1) for the control register. This is required for writing to control register 0 and control register 1. See Table 7. |
| NC | 32 | O | Not connected |
| REFIN | 28 | I | Common-mode reference input for the analog input channels. It is recommended that this pin be connected to the reference output REFOUT. |
| REFP | 26 | I | Reference input, requires a bypass capacitor of 10 μF to AGND in order to bypass the internal reference voltage. An external reference voltage at this input can be applied. This option can be programmed through control register 0. See Table 8. |
| REFM | 25 | I | Reference input, requires a bypass capacitor of 10 μF to AGND in order to bypass the internal reference voltage. An external reference voltage at this input can be applied. This option can be programmed through control register 0. See Table 8. |
| $\overline{\text{RESET}}$ | 31 | I | Hardware reset of the THS1209. Sets the control register to default values. |
| REFOUT | 27 | O | Analog fixed reference output voltage of 2.5 V. Sink and source capability of 250 μA . The reference output requires a capacitor of 10 μF to AGND for filtering and stability. |
| $\overline{\text{RD}}(1)$ | 19 | I | The $\overline{\text{RD}}$ input is used only if the $\overline{\text{WR}}$ input is configured as a write only input. In this case, it is a digital input, active low as a data read select from the processor. See timing section. |
| $\overline{\text{WR}}(\text{R}/\overline{\text{W}})(1)$ | 20 | I | This input is programmable. It functions as a read-write input ($\text{R}/\overline{\text{W}}$) and can also be configured as a write-only input ($\overline{\text{WR}}$), which is active low and used as data write select from the processor. In this case, the $\overline{\text{RD}}$ input is used as a read input from the processor. See timing section. |

(1) The start-conditions of $\overline{\text{RD}}$ and $\overline{\text{WR}}(\text{R}/\overline{\text{W}})$ are unknown. The first access to the ADC has to be a write access to initialize the ADC.

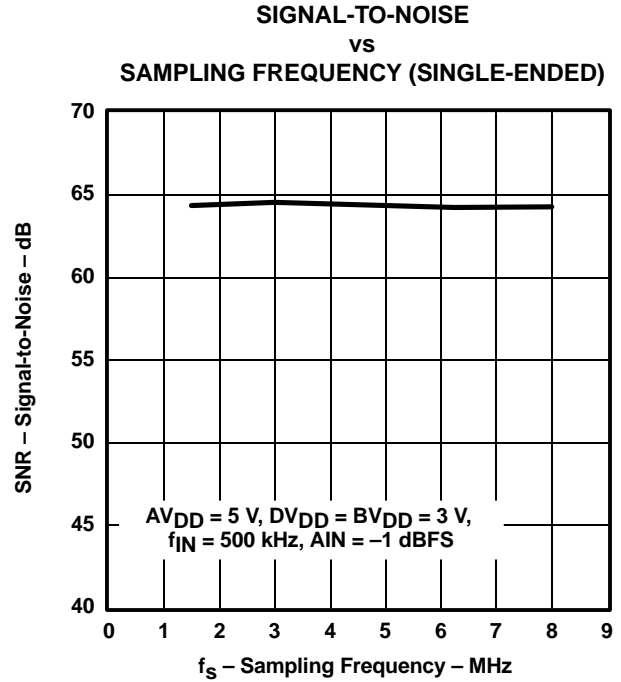
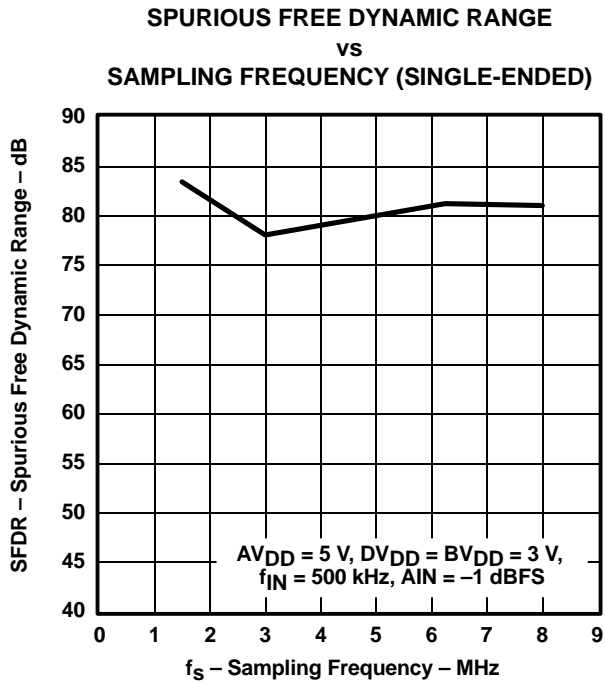
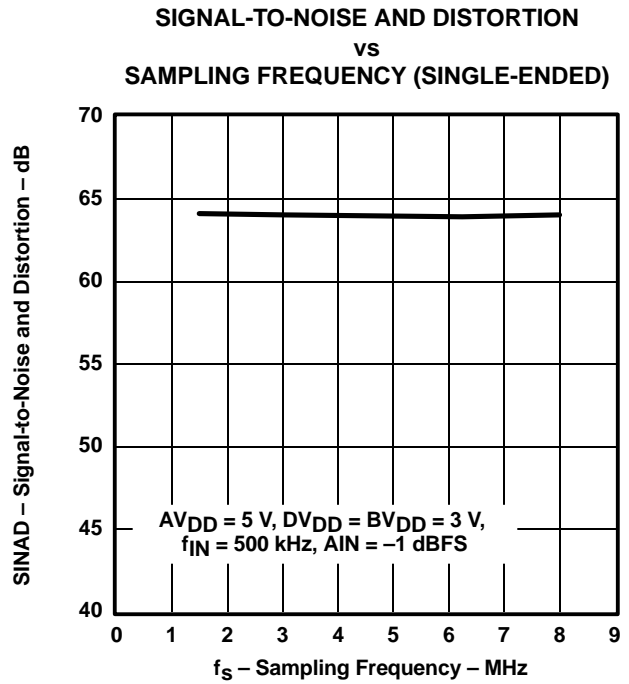
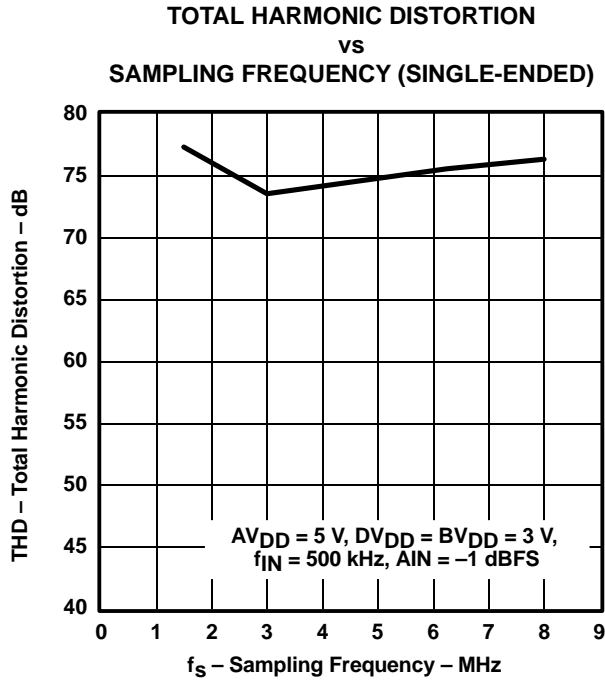
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FUNCTIONAL BLOCK DIAGRAM



TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

TOTAL HARMONIC DISTORTION
vs
SAMPLING FREQUENCY (DIFFERENTIAL)

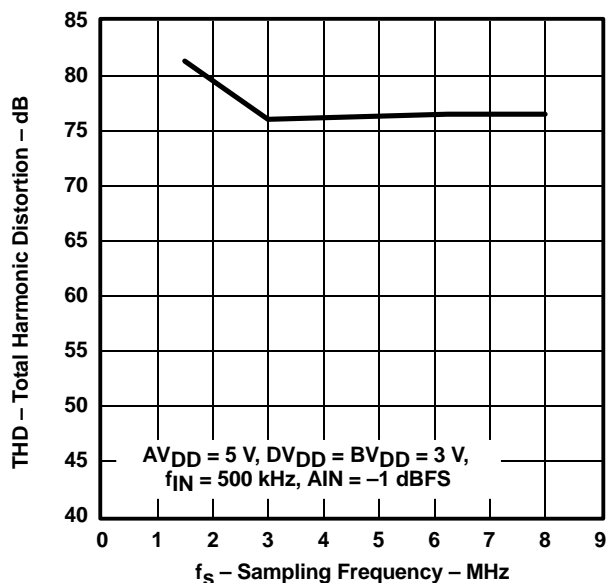


Figure 5

SIGNAL-TO-NOISE AND DISTORTION
vs
SAMPLING FREQUENCY (DIFFERENTIAL)

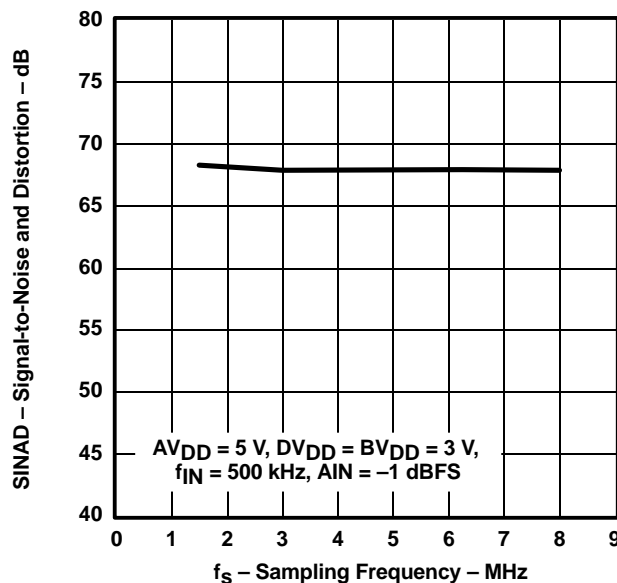


Figure 6

SPURIOUS FREE DYNAMIC RANGE
vs
SAMPLING FREQUENCY (DIFFERENTIAL)

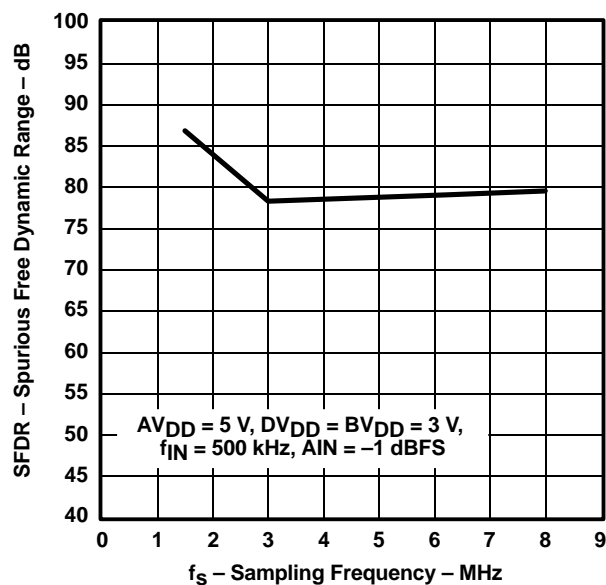


Figure 7

SIGNAL-TO-NOISE
vs
SAMPLING FREQUENCY (DIFFERENTIAL)

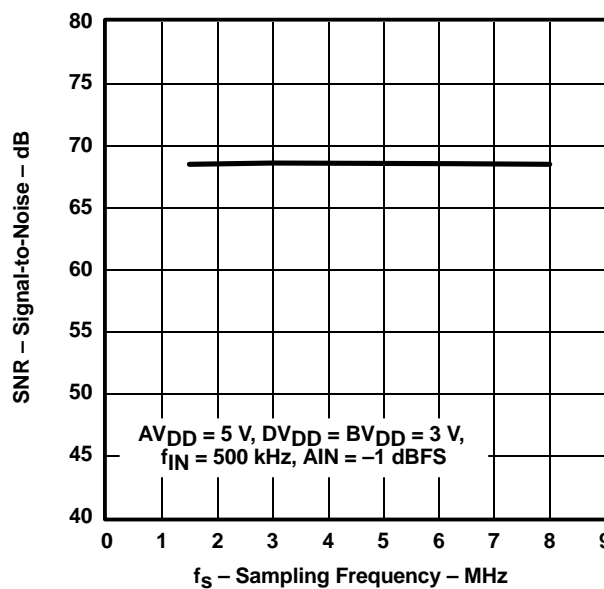


Figure 8

TYPICAL CHARACTERISTICS

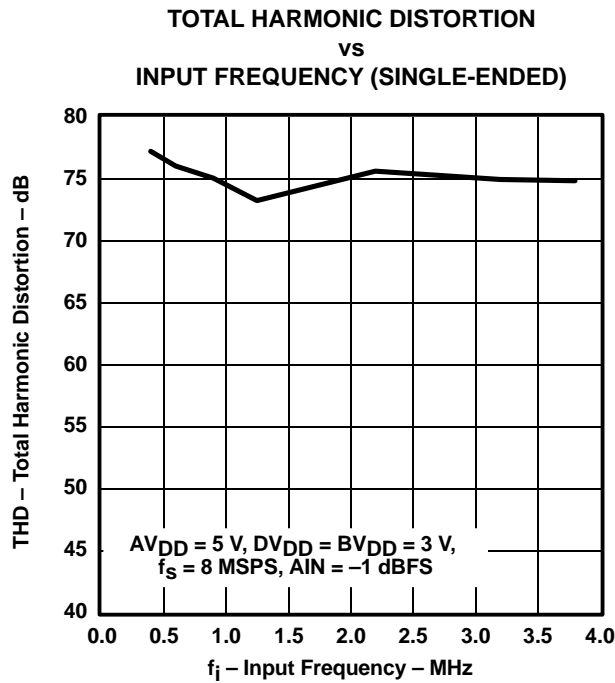


Figure 9

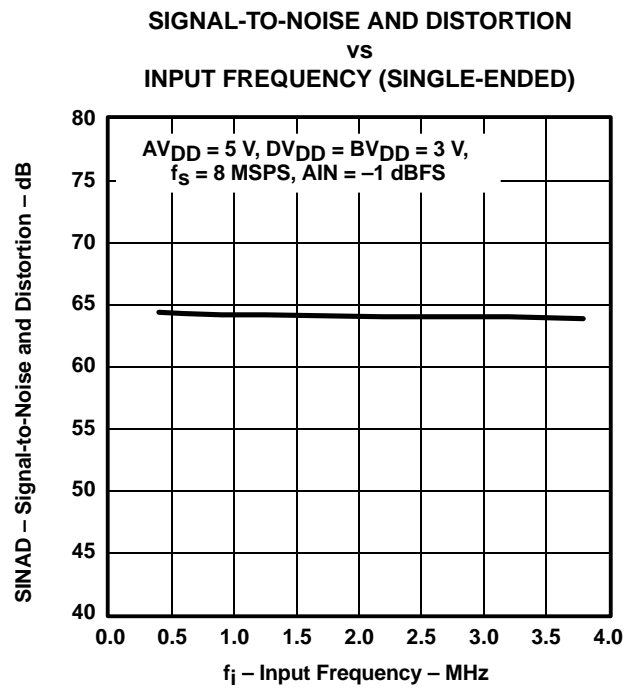


Figure 10

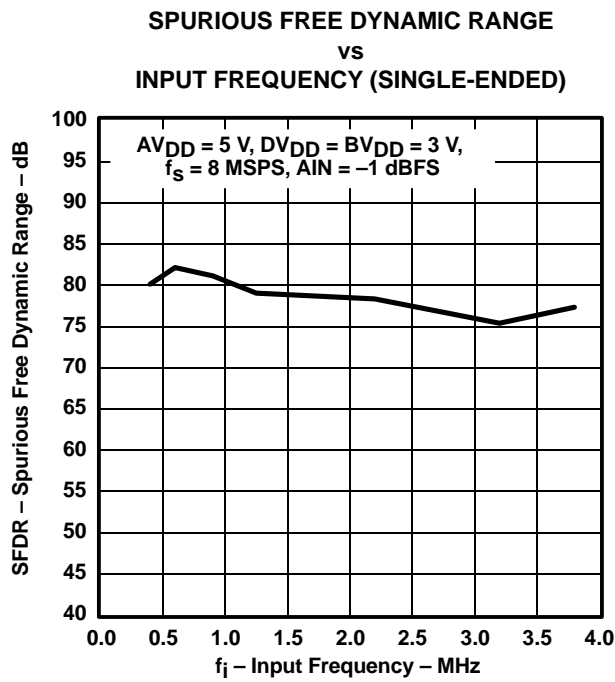


Figure 11

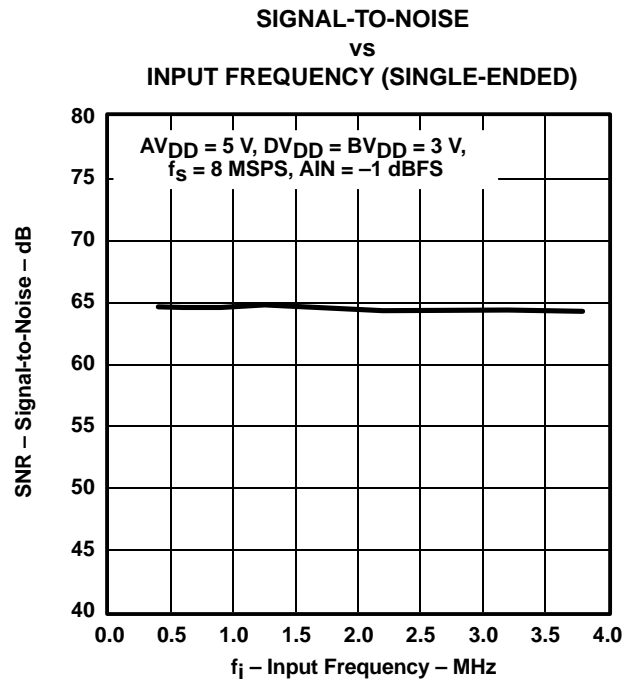
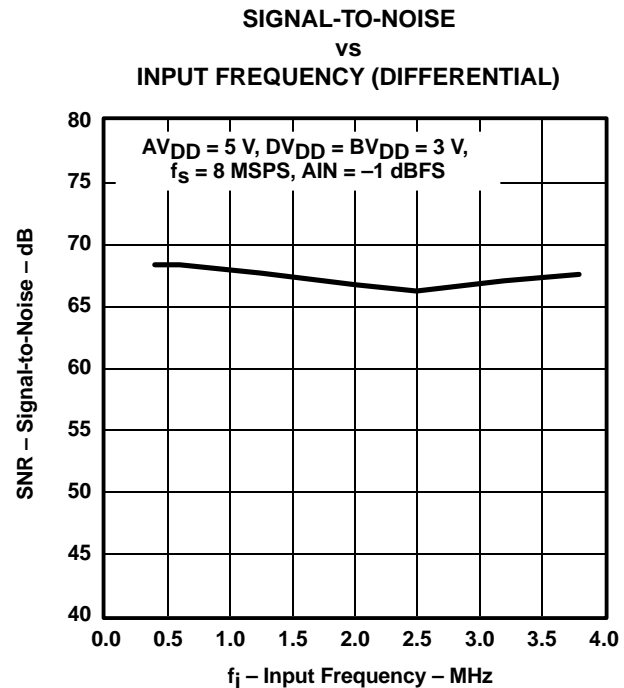
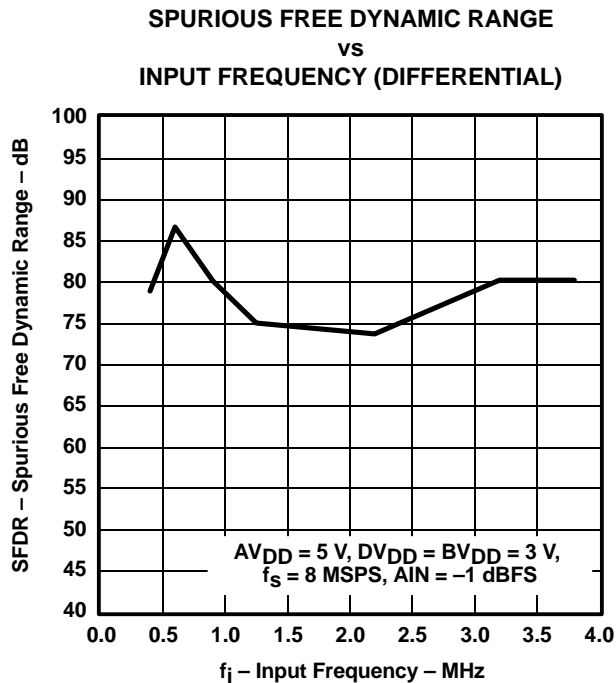
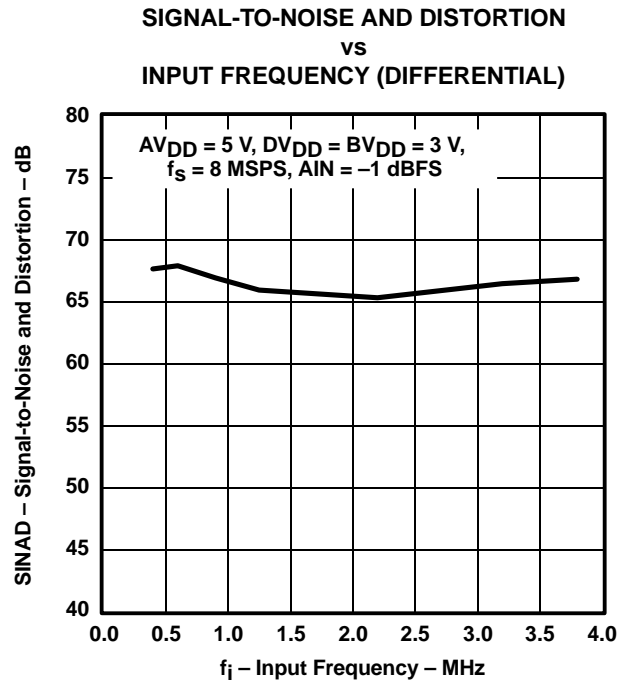
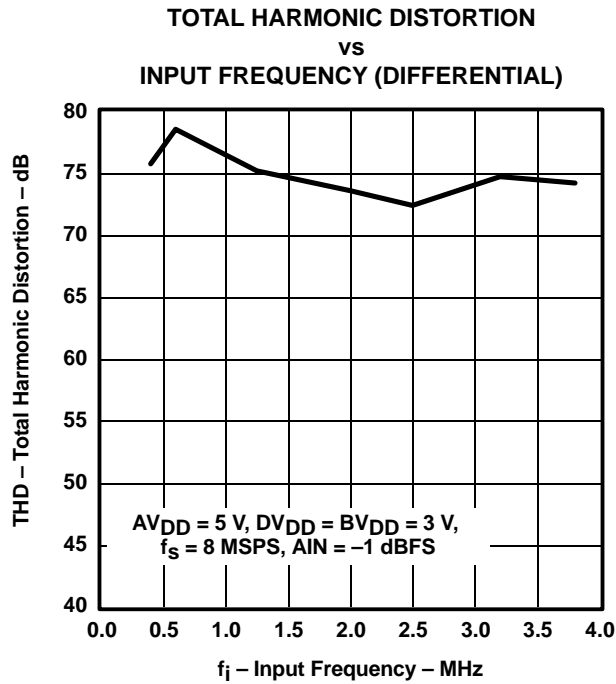
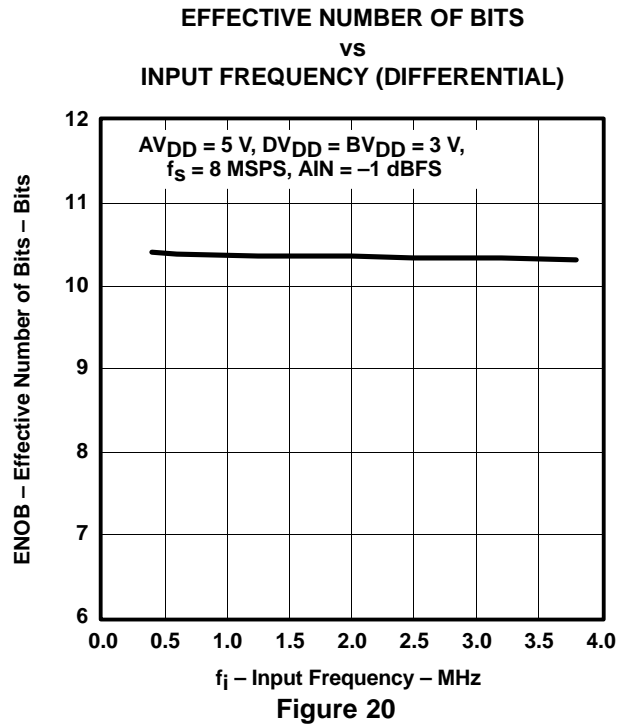
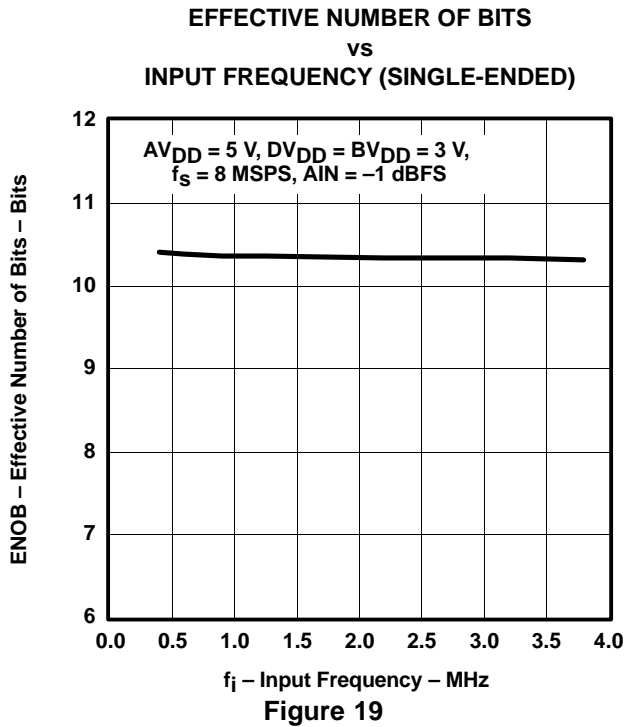
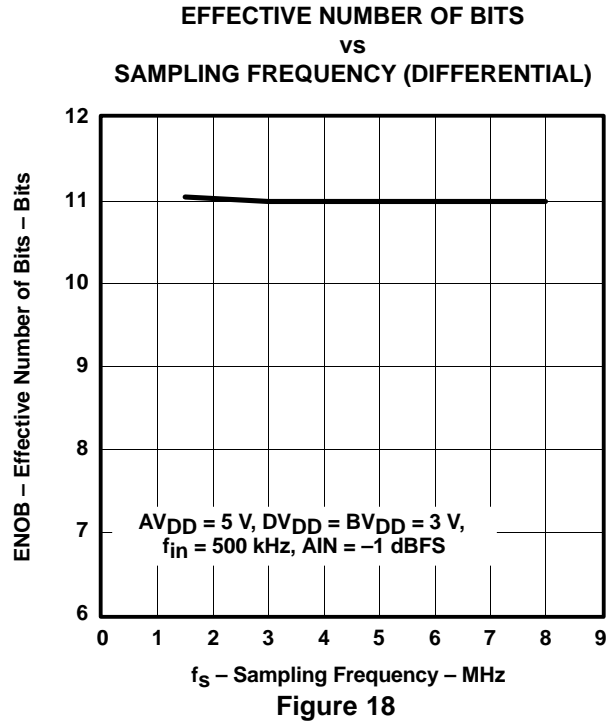
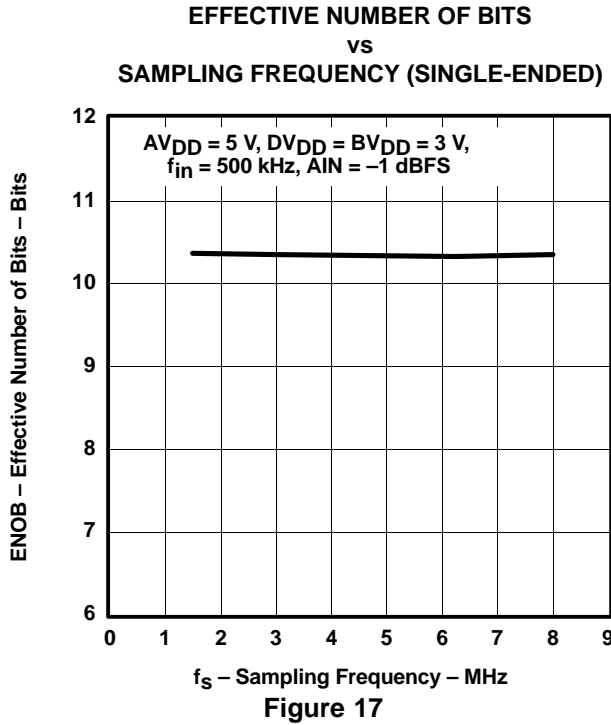


Figure 12

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

**DIFFERENTIAL NONLINEARITY
vs
ADC CODE**

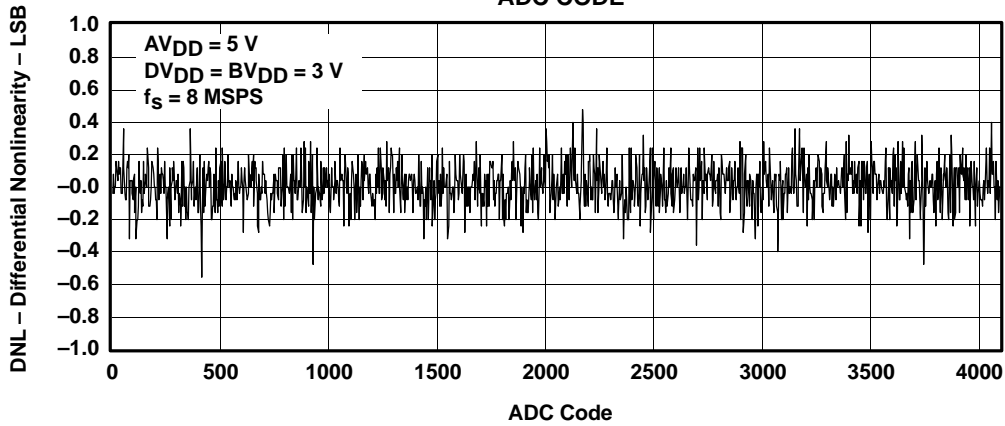


Figure 21

**INTEGRAL NONLINEARITY
vs
ADC CODE**

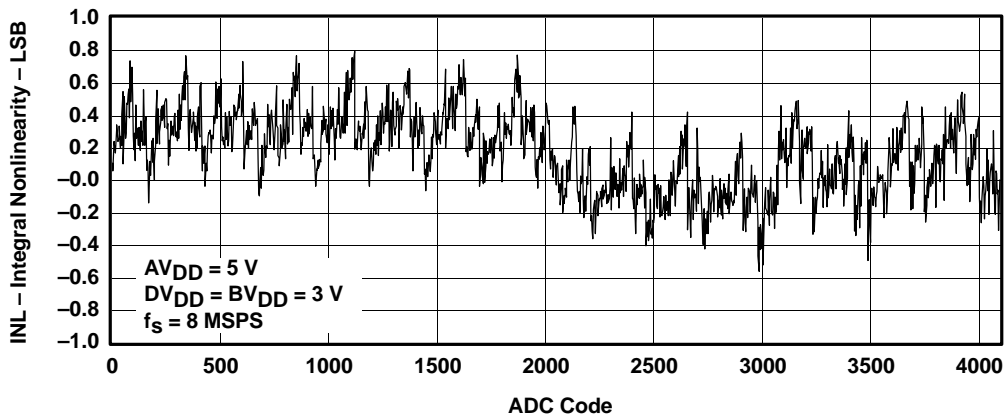


Figure 22

TYPICAL CHARACTERISTICS

FAST FOURIER TRANSFORM (4096 POINTS)
(SINGLE-ENDED)

vs
FREQUENCY

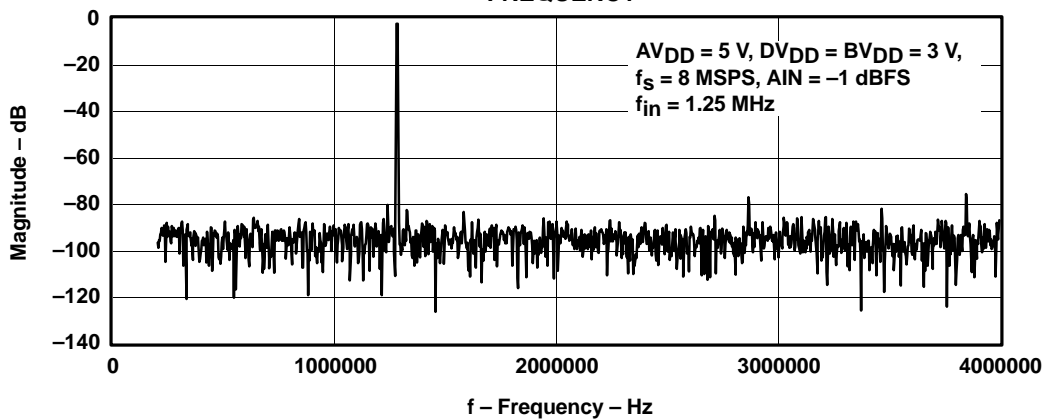


Figure 23

FAST FOURIER TRANSFORM (4096 POINTS)
(DIFFERENTIAL)

vs
FREQUENCY

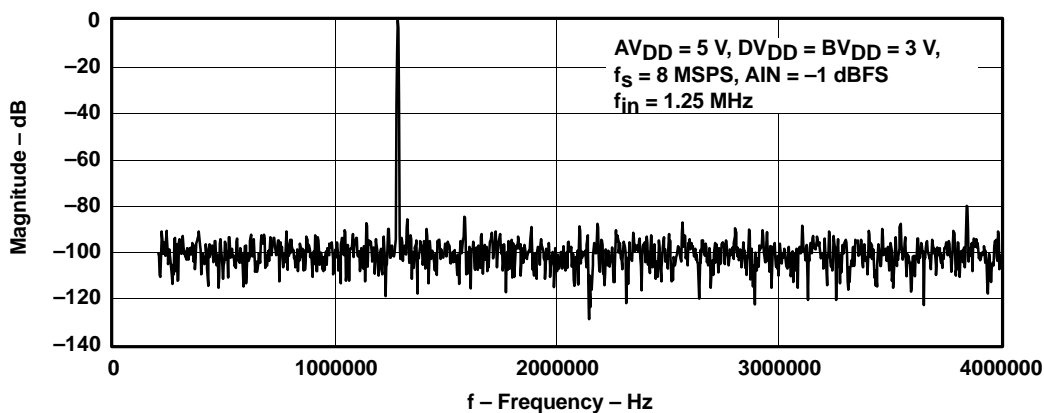


Figure 24

DETAILED DESCRIPTION

Reference Voltage

The THS1209 has a built-in reference, which provides the reference voltages for the ADC. VREFP is set to 3.5 V and VREFM is set to 1.5 V. An external reference can also be used through two reference input pins, REFP and REFM, if the reference source is programmed as external. The voltage levels applied to these pins establish the upper and lower limits of the analog inputs to produce a full-scale and zero-scale reading respectively.

Analog Inputs

The THS1209 consists of two analog inputs, which are sampled simultaneously. These inputs can be selected individually and configured as single-ended or differential inputs. The desired analog input channel can be programmed.

Converter

The THS1209 uses a 12-bit pipelined multistaged architecture which achieves a high sample rate with low power consumption. The THS1209 distributes the conversion over several smaller ADC sub-blocks, refining the conversion with progressively higher accuracy as the device passes the results from stage to stage. This distributed conversion requires a small fraction of the number of comparators used in a traditional flash ADC. A sample-and-hold amplifier (SHA) within each of the stages permits the first stage to operate on a new input sample while the second through the eighth stages operate on the seven preceding samples.

Conversion

An external clock signal with a duty cycle of 50% has to be applied to the clock input (CONV_CLK). A new conversion is started with every falling edge of the applied clock signal. The conversion values are available at the output with a latency of 5 clock cycles.

SYNC

In multichannel mode, the first SYNC signal is delayed by [7+ (# Channels Sampled)] cycles of the CONV_CLK after a SYNC reset. This is due to the latency of the pipeline architecture of the THS1209.

Sampling Rate

The maximum possible conversion rate per channel is dependent on the selected analog input channels. Table 1 shows the maximum conversion rate for different combinations.

Table 1. Maximum Conversion Rate

| CHANNEL CONFIGURATION | NUMBER OF CHANNELS | MAXIMUM CONVERSION RATE PER CHANNEL |
|-------------------------|--------------------|-------------------------------------|
| 1 single-ended channel | 1 | 8 MSPS |
| 2 single-ended channels | 2 | 4 MSPS |
| 1 differential channel | 1 | 8 MSPS |

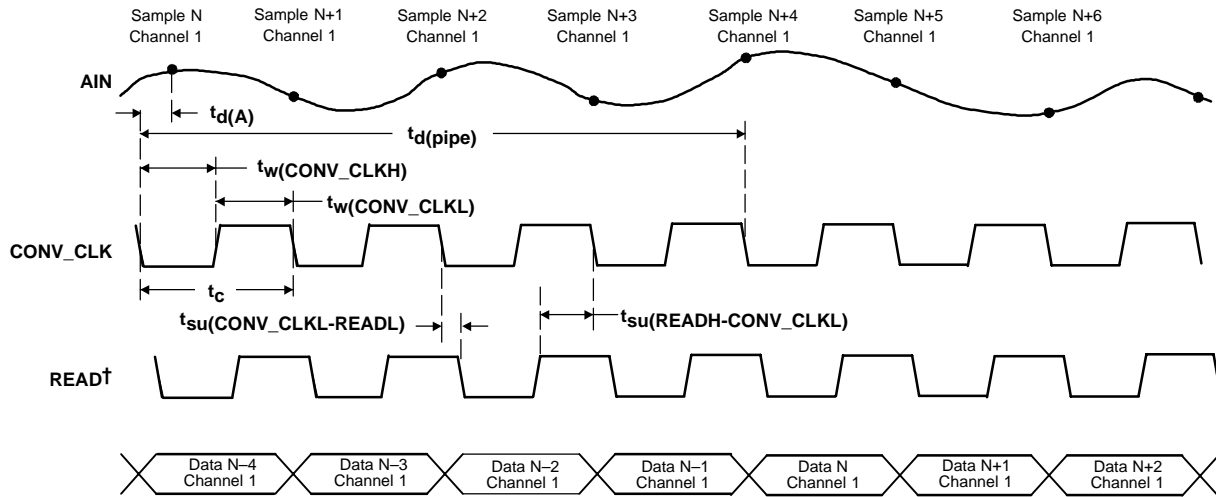
The maximum conversion rate in the continuous conversion mode per channel, f_c , is given by:

$$f_c = \frac{8 \text{ MSPS}}{\# \text{ channels}}$$

CONVERSION MODE

During conversion, the ADC operates with a free running external clock signal applied to the input CONV_CLK. With every falling edge of the CONV_CLK signal a new converted value is available to the databus with the corresponding read signal. The THS1209 offers up to two analog inputs to be selected. It is important to provide the channel information to the system, this means to know which channel is available to the databus. The signal SYNC is disabled for the selection of one analog input since this information is not required for one analog input.

Figure 25 shows the timing of the conversion when one analog input channel is selected. The maximum throughput rate is 8 MSPS in this mode. There is a certain timing relationship required for the read signal with respect to the conversion clock. This can be seen in Figure 26 and Table 2. A more detailed description of the timing is given in the section timing and signal description of the THS1209.



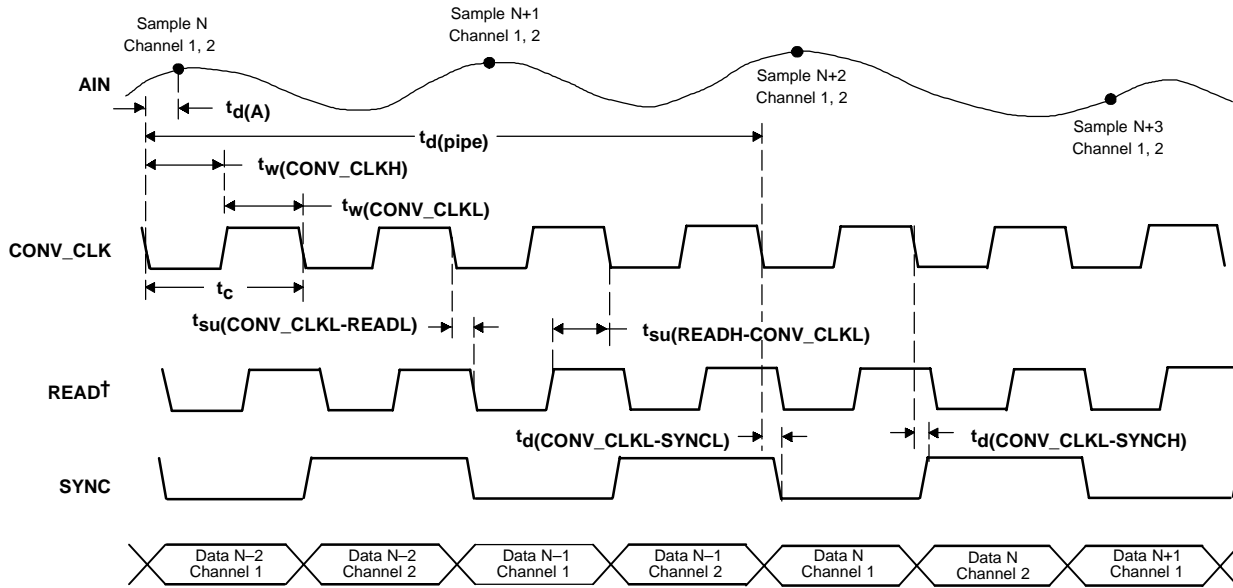
†READ is the logical combination from $\overline{CS0}$, CS1 and \overline{RD}

Figure 25. Conversion Timing in 1-Channel Operation

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Figure 26 shows the conversion timing when two analog input channels are selected. The maximum throughput rate per channel is 4 MSPS in this mode. The data flow in the bottom of the figure shows the order the converted data is available to the data bus. The SYNC signal is always active low if data of channel 1 is available to the data bus. There is a certain timing relationship required for the read signal with respect to the conversion clock. This can be seen in Figure 26 and with the timing specifications. A more detailed description of the timing is given in the section timing and signal description of the THS1209.



†READ is the logical combination from $\overline{CS0}$, CS1 and \overline{RD}

Figure 26. Conversion Timing in 2 Channel Operation

DIGITAL OUTPUT DATA FORMAT

The digital output data format of the THS1209 can be in either binary format or in twos complement format. The following tables list the digital outputs for the analog input voltages.

Table 2. Binary Output Format for Single-Ended Configuration

| SINGLE-ENDED, BINARY OUTPUT | |
|------------------------------------|---------------------|
| ANALOG INPUT VOLTAGE | DIGITAL OUTPUT CODE |
| $A_{IN} = V_{REFP}$ | FFFh |
| $A_{IN} = (V_{REFP} + V_{REFM})/2$ | 800h |
| $A_{IN} = V_{REFM}$ | 000h |

Table 3. Twos Complement Output Format for Single-Ended Configuration

| SINGLE-ENDED, TWOS COMPLEMENT | |
|------------------------------------|---------------------|
| ANALOG INPUT VOLTAGE | DIGITAL OUTPUT CODE |
| $A_{IN} = V_{REFP}$ | 7FFh |
| $A_{IN} = (V_{REFP} + V_{REFM})/2$ | 000h |
| $A_{IN} = V_{REFM}$ | 800h |

Table 4. Binary Output Format for Differential Configuration

| DIFFERENTIAL, BINARY OUTPUT | |
|---|---------------------|
| ANALOG INPUT VOLTAGE | DIGITAL OUTPUT CODE |
| $V_{in} = A_{INP} - A_{INM}$ $V_{REF} = V_{REFP} - V_{REFM}$ | |
| $V_{in} = V_{REF}$ | FFFh |
| $V_{in} = 0$ | 800h |
| $V_{in} = -V_{REF}$ | 000h |

Table 5. Twos Complement Output Format for Differential Configuration

| DIFFERENTIAL, TWOS COMPLEMENT | |
|---|---------------------|
| ANALOG INPUT VOLTAGE | DIGITAL OUTPUT CODE |
| $V_{in} = A_{INP} - A_{INM}$ $V_{REF} = V_{REFP} - V_{REFM}$ | |
| $V_{in} = V_{REF}$ | 7FFh |
| $V_{in} = 0$ | 000h |
| $V_{in} = -V_{REF}$ | 800h |

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ADC CONTROL REGISTER

The THS1209 contains two 10-bit wide control registers (CR0, CR1) in order to program the device into the desired mode. The bit definitions of both control registers are shown in Table 7.

Table 6. Bit Definitions of Control Register CR0 and CR1

| REG | BIT 9 | BIT 8 | BIT 7 | BIT 6 | BIT 5 | BIT 4 | BIT 3 | BIT 2 | BIT 1 | BIT 0 |
|-----|-------|--------|---------|-------|-------|--------|--------|-------|-------|-------|
| CR0 | TEST1 | TEST0 | SCAN | DIFF1 | DIFF0 | CHSEL1 | CHSEL0 | PD | RES | VREF |
| CR1 | RBACK | OFFSET | BIN/2's | R/W | RES | RES | RES | RES | SRST | RESET |

Writing to Control Register 0 and Control Register 1

The 10-bit wide control register 0 and control register 1 can be programmed by addressing the desired control register and writing the register value to the ADC. The addressing is performed with the upper data bits D10 and D11, which function in this case as address lines RA0 and RA1. During this write process, the data bits D0 to D9 contain the desired control register value. Table 8 shows the addressing of each control register.

Table 7. Control Register Addressing

| D0 – D9 | D10/RA0 | D11/RA1 | Addressed Control Register |
|------------------------|---------|---------|----------------------------|
| Desired register value | 0 | 0 | Control register 0 |
| Desired register value | 1 | 0 | Control register 1 |
| Desired register value | 0 | 1 | Reserved for future |
| Desired register value | 1 | 1 | Reserved for future |

INITIALIZATION OF THE THS1209

The initialization of the THS1209 should be done according to the configuration flow shown in Figure 27.

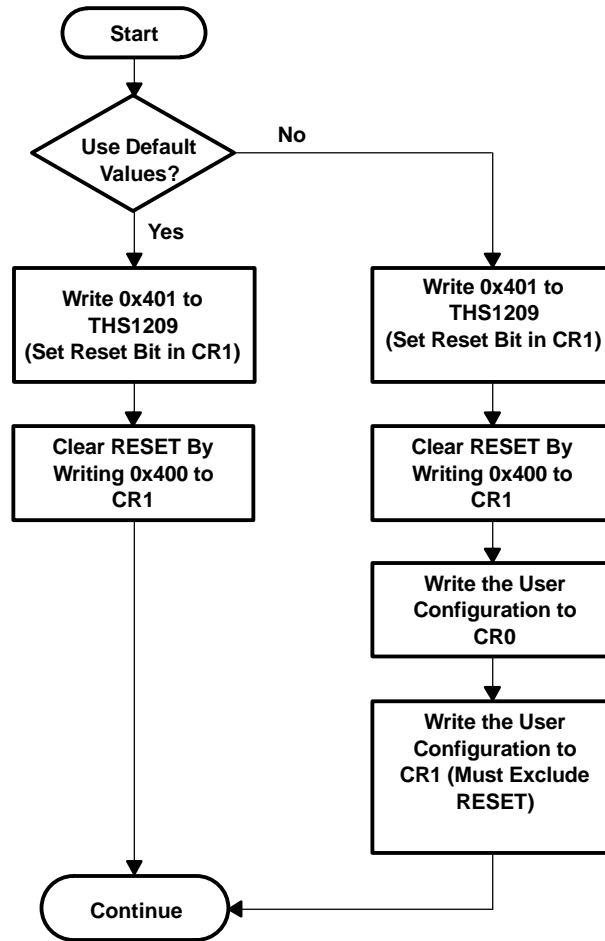


Figure 27. THS1209 Configuration Flow

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ADC CONTROL REGISTERS

Control Register 0 (see Table 8)

| BIT 11 | BIT 10 | BIT 9 | BIT 8 | BIT 7 | BIT 6 | BIT 5 | BIT 4 | BIT 3 | BIT 2 | BIT 1 | BIT 0 |
|--------|--------|-------|-------|-------|-------|-------|--------|--------|-------|-------|-------|
| 0 | 0 | TEST1 | TEST0 | SCAN | DIFF1 | DIFF0 | CHSEL1 | CHSEL0 | PD | RES | VREF |

Table 8. Control Register 0 Bit Functions

| BITS | RESET VALUE | NAME | FUNCTION |
|------|-------------|-------------------|--|
| 0 | 0 | VREF | Vref select: Bit 0 = 0 → The internal reference is selected. Bit 0 = 1 → The external reference voltage is selected. |
| 1 | 0 | RES | Reserved |
| 2 | 0 | PD | Power down. Bit 2 = 0 → The ADC is active. Bit 2 = 1 → Power down The reading and writing to and from the digital outputs is possible during power down. |
| 3, 4 | 0,0 | CHSEL0, CHSEL1 | Channel select Bit 3 and bit 4 select the analog input channel of the ADC. Refer to Table 9. |
| 5,6 | 1,0 | DIFF0, DIFF1 | Number of differential channels Bit 5 and bit 6 contain information about the number of selected differential channels. Refer to Table 9. |
| 7 | 0 | SCAN | Autoscan enable Bit 7 enables or disables the autoscan function of the ADC. Refer to Table 9. |
| 8,9 | 0,0 | TEST0, TEST1 | Test input enable Bit 8 and bit 9 control the test function of the ADC. Three different test voltages can be measured. This feedback allows the check of all hardware connections and the ADC operation. Refer to Table 10 for selection of the three different test voltages. |

ANALOG INPUT CHANNEL SELECTION

The analog input channels of the THS1209 can be selected via bits 3 to 7 of control register 0. One single channel (single-ended or differential) is selected via bit 3 and bit 4 of control register 0. Bit 5 controls the selection between single-ended and differential configuration. Bit 6 and bit 7 select the autoscan mode, if more than one input channel is selected. Table 9 shows the possible selections.

Table 9. Analog Input Channel Configurations

| BIT 7 AS | BIT 6 DF1 | BIT 5 DF0 | BIT 4 CHS1 | BIT 3 CHS0 | DESCRIPTION OF THE SELECTED INPUTS |
|-------------|--------------|--------------|---------------|---------------|---|
| 0 | 0 | 0 | 0 | 0 | Analog input AINP (single ended) |
| 0 | 0 | 0 | 0 | 1 | Analog input AINM (single ended) |
| 0 | 0 | 0 | 1 | 0 | Reserved |
| 0 | 0 | 0 | 1 | 1 | Reserved |
| 0 | 0 | 1 | 0 | 0 | Differential channel (AINP–AINM) |
| 0 | 0 | 1 | 0 | 1 | Reserved |
| 1 | 0 | 0 | 0 | 1 | Autoscan two single ended channels: AINP, AINM, AINP, ... |
| 1 | 0 | 0 | 1 | 0 | Reserved |
| 1 | 0 | 0 | 1 | 1 | Reserved |
| 1 | 1 | 0 | 0 | 1 | Reserved |
| 1 | 0 | 1 | 0 | 1 | Reserved |
| 1 | 0 | 1 | 1 | 0 | Reserved |
| 0 | 0 | 1 | 1 | 0 | Reserved |
| 0 | 0 | 1 | 1 | 1 | Reserved |
| 1 | 0 | 0 | 0 | 0 | Reserved |
| 1 | 0 | 1 | 0 | 0 | Reserved |
| 1 | 0 | 1 | 1 | 1 | Reserved |
| 1 | 1 | 0 | 0 | 0 | Reserved |
| 1 | 1 | 0 | 1 | 0 | Reserved |
| 1 | 1 | 0 | 1 | 1 | Reserved |
| 1 | 1 | 1 | 0 | 0 | Reserved |
| 1 | 1 | 1 | 0 | 1 | Reserved |
| 1 | 1 | 1 | 1 | 0 | Reserved |
| 1 | 1 | 1 | 1 | 1 | Reserved |

Test Mode

The test mode of the ADC is selected via bit 8 and bit 9 of control register 0. The different selections are shown in Table 10.

Table 10. Test Mode

| BIT 9 TEST1 | BIT 8 TEST0 | OUTPUT RESULT |
|----------------|----------------|-----------------------------|
| 0 | 0 | Normal mode |
| 0 | 1 | V_{REFP} |
| 1 | 0 | $((V_{REFM})+(V_{REFP}))/2$ |
| 1 | 1 | V_{REFM} |

Three different options can be selected. This feature allows support testing of hardware connections between the ADC and the processor.

Control Register 1 (see Table 8)

| BIT 11 | BIT 10 | BIT 9 | BIT 8 | BIT 7 | BIT 6 | BIT 5 | BIT 4 | BIT 3 | BIT 2 | BIT 1 | BIT 0 |
|--------|--------|-------|--------|--------|-------|-------|-------|-------|-------|-------|-------|
| 0 | 1 | RBACK | OFFSET | BIN/2s | R/W | RES | RES | RES | RES | SRST | RESET |

Table 11. Control Register 1 Bit Functions

| BITS | RESET VALUE | NAME | FUNCTION |
|------|-------------|--------|---|
| 0 | 0 | RESET | Reset Writing a 1 into this bit resets the device and sets the control register 0 and control register 1 to the reset values. To bring the device out of reset, a 0 has to be written into this bit. |
| 1 | 0 | SRST | Writing a 1 into this bit resets the sync generator. When running in multichannel mode, this must be set during the configuration cycle. |
| 2, 3 | 0,0 | RES | Always write 0 |
| 4 | 1 | RES | Always write 0 |
| 5 | 1 | RES | Always write 0 |
| 6 | 0 | R/W | R/W, RD/W \overline{R} selection Bit 6 of control register 1 controls the function of the inputs \overline{RD} and \overline{WR} . When bit 6 in control register 1 is set to 1, WR becomes a R/W input and RD is disabled. From now on a read is signalled with R/W high and a write with R/W as a low signal. If bit 6 in control register 1 is set to 0, the input RD becomes a read input and the input WR becomes a write input. |
| 7 | 0 | BIN/2s | Complement select If bit 7 of control register 1 is set to 0, the output value of the ADC is in twos complement. If bit 7 of control register 1 is set to 1, the output value of the ADC is in binary format. Refer to Table 2 through Table 5. |
| 8 | 0 | OFFSET | Offset cancellation mode Bit 8 = 0 → normal conversion mode Bit 8 = 1 → offset calibration mode If a 1 is written into bit 8 of control register 1, the device internally sets the inputs to zero and does a conversion. The conversion result is stored in an offset register and subtracted from all conversions in order to reduce the offset error. |
| 9 | 0 | RBACK | Debug mode Bit 9 = 0 → normal conversion mode Bit 9 = 1 → enable debug mode When bit 9 of control register 1 is set to 1, debug mode is enabled. In this mode, the contents of control register 0 and control register 1 can be read back. The first read after bit 9 is set to 1 contains the value of control register 0. The second read after bit 9 is set to 1 contains the value of control register 1. To bring the device back into normal conversion mode, this bit has to be set back to 0 by writing again to control register 1. |

Timing and Signal Description of the THS1209

The reading from the THS1209 and writing to the THS1209 is performed by using the chip select inputs ($\overline{CS0}$, CS1), the write input \overline{WR} and the read input \overline{RD} . The write input is configurable to a combined read/write input (R/\overline{W}). This is desired in cases where the connected processor consists of a combined read/write output signal (R/\overline{W}). The two chip select inputs can be used to interface easily to a processor.

Reading from the THS1209 takes place by an internal \overline{RD}_{int} signal, which is generated from the logical combination of the external signals $\overline{CS0}$, CS1 and \overline{RD} (see Figure 4). This signal is then used to strobe the words out and to enable the output buffers. The last external signal (either $\overline{CS0}$, CS1 or \overline{RD}) to become valid makes \overline{RD}_{int} active while the write input (\overline{WR}) is inactive. The first of those external signals going to its inactive state then deactivates \overline{RD}_{int} again.

Writing to the THS1209 takes place by an internal \overline{WR}_{int} signal, which is generated from the logical combination of the external signals $\overline{CS0}$, CS1 and \overline{WR} . This signal is then used to strobe the control words into the control registers 0 and 1. The last external signal (either $\overline{CS0}$, CS1 or \overline{WR}) to become valid makes \overline{WR}_{int} active while the read input (\overline{RD}) is inactive. The first of those external signals going to its inactive state then deactivates \overline{WR}_{int} again.

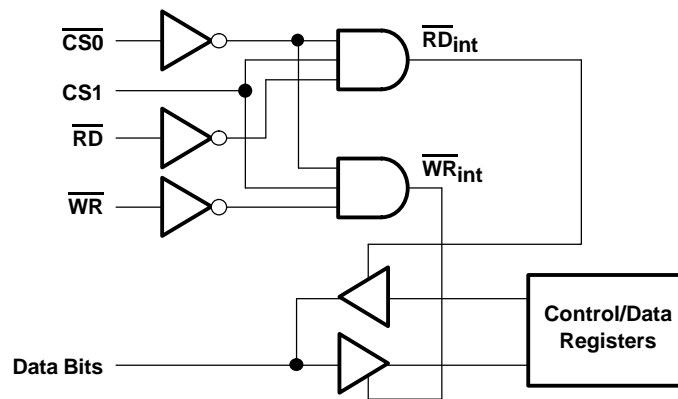


Figure 28. Logical Combination of $\overline{CS0}$, CS1, \overline{RD} , and \overline{WR}

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Read Timing (using \overline{RD} , \overline{RD} -controlled)

Figure 29 shows the read-timing behavior when the $\overline{WR}(R/\overline{W})$ input is programmed as a write-input only. The input \overline{RD} acts as the read-input in this configuration. This timing is called \overline{RD} -controlled because \overline{RD} is the last external signal of $\overline{CS0}$, $\overline{CS1}$, and \overline{RD} which becomes valid.

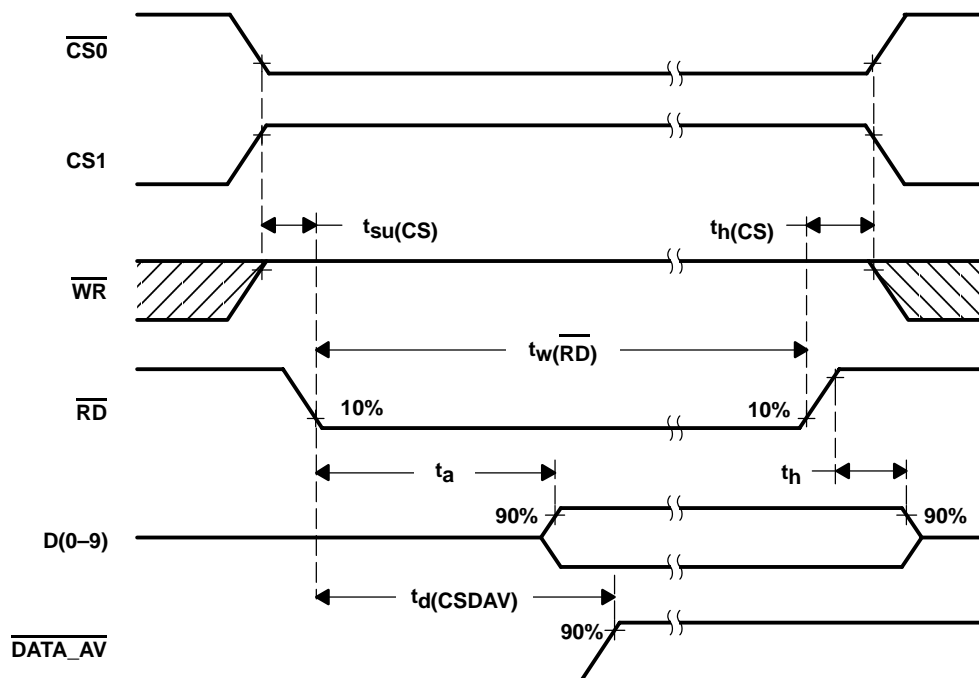


Figure 29. Read Timing Diagram Using \overline{RD} (\overline{RD} -controlled)

Read Timing Parameter (\overline{RD} -controlled)

| PARAMETER | | MIN | TYP | MAX | UNIT |
|-------------------------|---|-----|-----|-----|------|
| $t_{su}(\overline{CS})$ | Setup time, \overline{RD} low to last CS valid | 0 | | | ns |
| t_a | Access time, last CS valid to data valid | 0 | | 10 | ns |
| $t_d(\overline{CSDAV})$ | Delay time, last CS valid to $\overline{DATA_AV}$ inactive | | 12 | | ns |
| t_h | Hold time, first CS invalid to data invalid | 0 | | 5 | ns |
| $t_h(\overline{CS})$ | Hold time, \overline{RD} change to first CS invalid | 5 | | | ns |
| $t_w(\overline{RD})$ | Pulse duration, \overline{RD} active | 10 | | | ns |

Write Timing (using \overline{WR} , \overline{WR} -controlled)

Figure 30 shows the write-timing behavior when the \overline{WR} (R/ \overline{W}) input is programmed as a write input \overline{WR} only. The input \overline{RD} acts as the read input in this configuration. This timing is called \overline{WR} -controlled because \overline{WR} is the last external signal of $\overline{CS0}$, $\overline{CS1}$, and \overline{WR} which becomes valid.

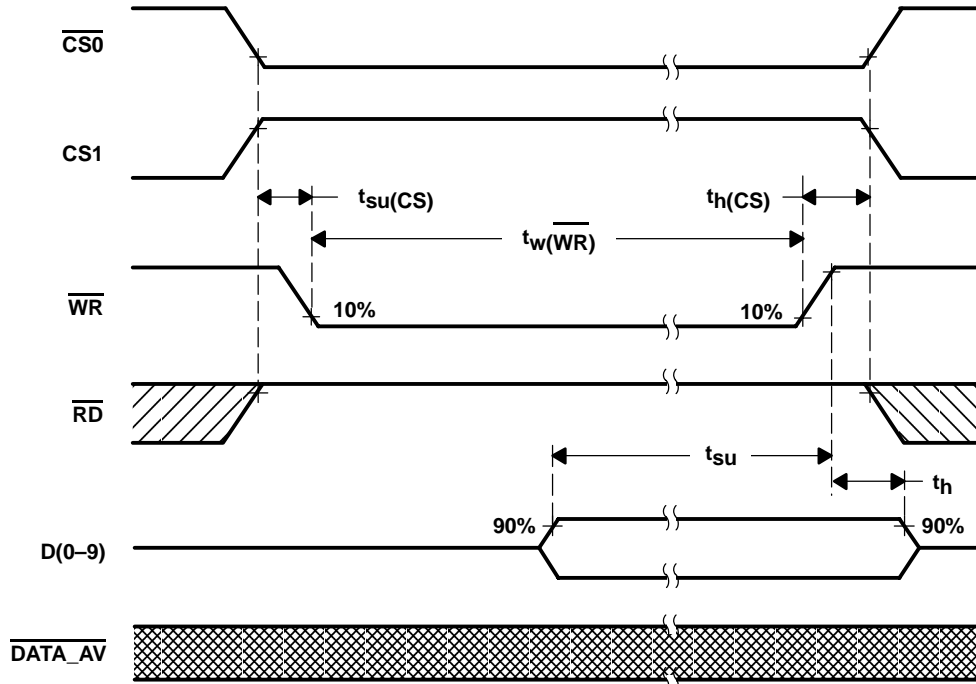


Figure 30. Write Timing Diagram Using \overline{WR} (\overline{WR} -controlled)

Write Timing Parameter Using \overline{WR} (\overline{WR} -controlled)

| PARAMETER | | MIN | TYP | MAX | UNIT |
|--------------|---|-----|-----|-----|------|
| $t_{su}(CS)$ | Setup time, CS stable to last \overline{WR} valid | 0 | | | ns |
| t_{su} | Setup time, data valid to first \overline{WR} invalid | 5 | | | ns |
| t_h | Hold time, \overline{WR} invalid to data invalid | 2 | | | ns |
| $t_h(CS)$ | Hold time, \overline{WR} invalid to CS change | 5 | | | ns |
| $t_w(WR)$ | Pulse duration, \overline{WR} active | 10 | | | ns |

Read Timing (using $\overline{R/W}$, $\overline{CS0}$ -controlled)

Figure 5 shows the read-timing behavior when the $\overline{WR}(\overline{R/W})$ input is programmed as a combined read-write input $\overline{R/W}$. The \overline{RD} input has to be tied to high-level in this configuration. This timing is called $\overline{CS0}$ -controlled because $\overline{CS0}$ is the last external signal of $\overline{CS0}$, $\overline{CS1}$, and $\overline{R/W}$ which becomes valid. The reading of the data should be done with a certain timing relative to the conversion clock CONV_CLK , as illustrated in Figure 31.

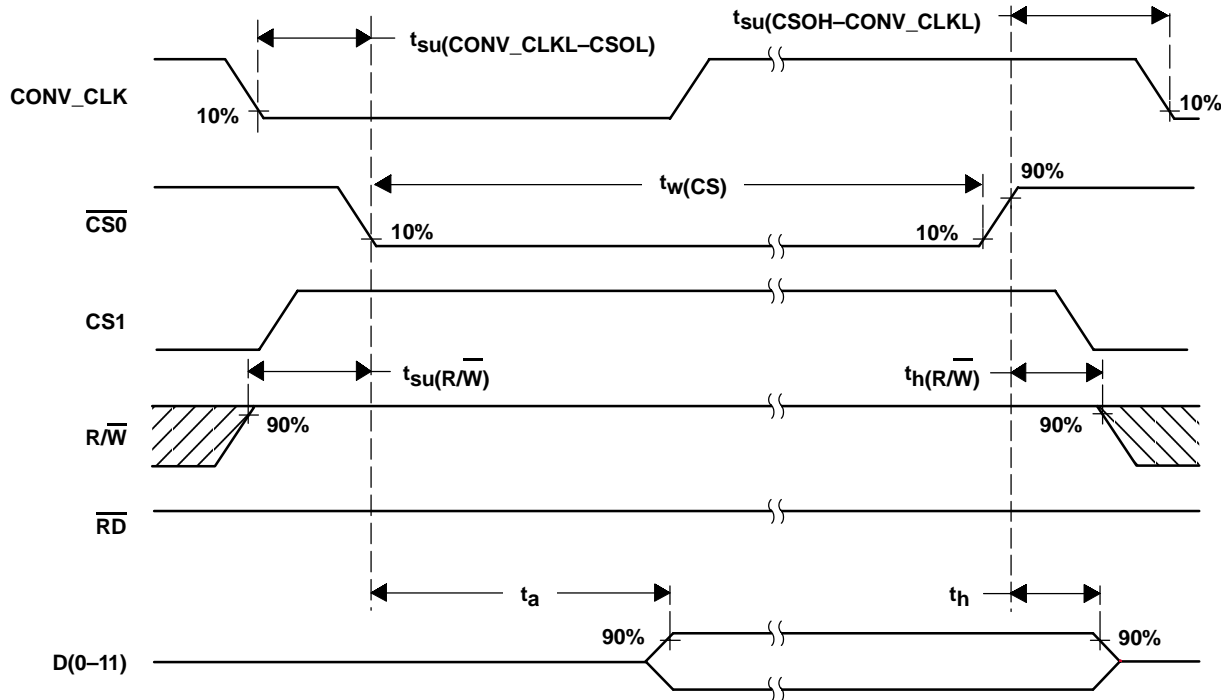


Figure 31. Read Timing Diagram Using $\overline{R/W}$ ($\overline{CS0}$ -controlled)

Read Timing Parameter ($\overline{CS0}$ -controlled)(1)

| PARAMETER | | MIN | TYP | MAX | UNIT |
|-----------------------------------|---|-----|-----|-----|------|
| $t_{su}(\text{CONV_CLKL_CSOL})$ | Setup time, CONV_CLK low before CS valid | 10 | | | ns |
| $t_{su}(\text{CSOH-CONV_CLKL})$ | Setup time, CS invalid to CONV_CLK low | 20 | | | ns |
| $t_{su}(\overline{R/W})$ | Setup time, $\overline{R/W}$ high to last CS valid | 0 | | | ns |
| t_a | Access time, last CS valid to data valid | 0 | | 10 | ns |
| t_h | Hold time, first CS invalid to data invalid | 0 | | 5 | ns |
| $t_h(\overline{R/W})$ | Hold time, first external CS invalid to $\overline{R/W}$ change | 5 | | | ns |
| $t_w(\overline{CS})$ | Pulse duration, CS active | 10 | | | ns |

(1) $\text{CS} = \overline{\text{CS0}}$

Write Timing (using $\overline{R/W}$, $\overline{CS0}$ -controlled)

Figure 32 shows the write-timing behavior when the $\overline{WR}(\overline{R/W})$ input is programmed as a combined read-write input $\overline{R/W}$. The \overline{RD} input has to be tied to high-level in this configuration. This timing is called $\overline{CS0}$ -controlled because $\overline{CS0}$ is the last external signal of $\overline{CS0}$, $\overline{CS1}$, and $\overline{R/W}$ which becomes valid. The writing to the THS1209 can be performed irrespective of the conversion clock signal CONV_CLK .

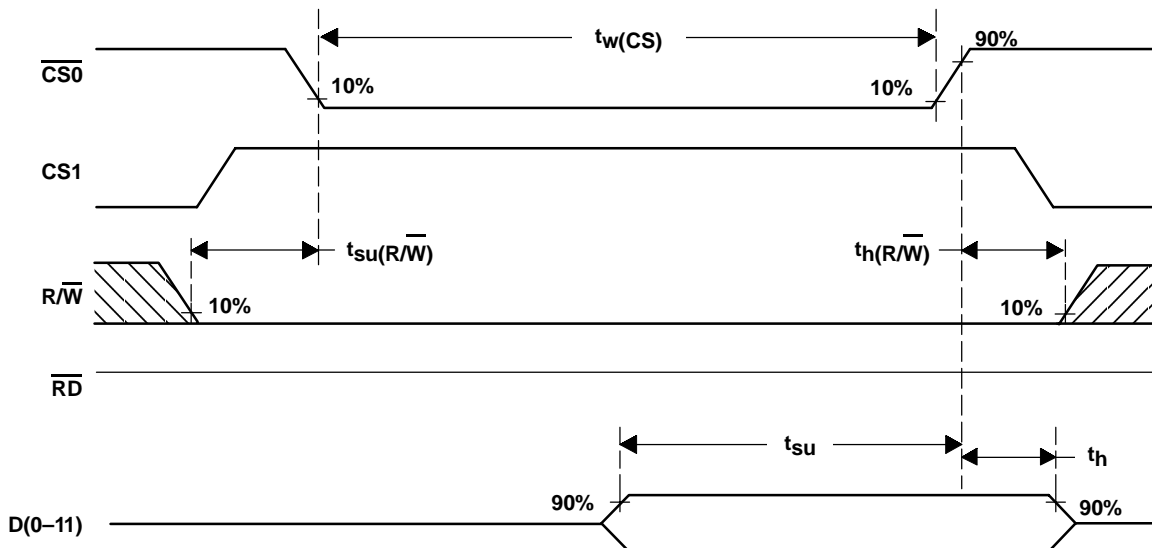


Figure 32. Write Timing Diagram Using $\overline{R/W}$ ($\overline{CS0}$ -controlled)

Write Timing Parameter ($\overline{CS0}$ -controlled)

| PARAMETER | | MIN | TYP | MAX | UNIT |
|--------------------------|--|-----|-----|-----|------|
| $t_{su}(\overline{R/W})$ | Setup time, $\overline{R/W}$ stable to last CS valid | 0 | | | ns |
| t_{su} | Setup time, data valid to first CS invalid | 5 | | | ns |
| t_h | Hold time, first CS invalid to data invalid | 2 | | | ns |
| $t_h(\overline{R/W})$ | Hold time, first CS invalid to $\overline{R/W}$ change | 5 | | | ns |
| $t_w(\overline{CS})$ | Pulse duration, CS active | 10 | | | ns |

ANALOG INPUT CONFIGURATION AND REFERENCE VOLTAGE

The THS1209 features two analog input channels. These can be configured for either single-ended or differential operation. Figure 33 shows a simplified model, where a single-ended configuration for channel AINP is selected. The reference voltages for the ADC itself are V_{REFP} and V_{REFM} (either internal or external reference voltage). The analog input voltage range goes from V_{REFM} to V_{REFP} . This means that V_{REFM} defines the minimum voltage, and V_{REFP} defines the maximum voltage, which can be applied to the ADC. The internal reference source provides the voltage V_{REFM} of 1.5 V and the voltage V_{REFP} of 3.5 V. The resulting analog input voltage swing of 2 V can be expressed by:

$$V_{REFM} \leq AINP \leq V_{REFP} \quad (1)$$

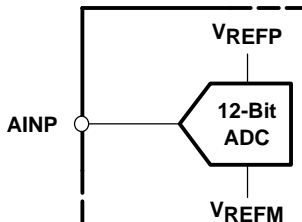


Figure 33. Single-Ended Input Stage

A differential operation is desired for many applications due to a better signal-to-noise ratio. Figure 34 shows a simplified model for the analog inputs AINM and AINP, which are configured for differential operation. The differential operation mode provides in terms of performance benefits over the single-ended mode and is therefore recommended for best performance. The THS1209 offers 1 differential analog input and in the single-ended mode 2 analog inputs. If the analog input architecture is differential, common-mode noise and common-mode voltages can be rejected. Additional details for both modes are given below.

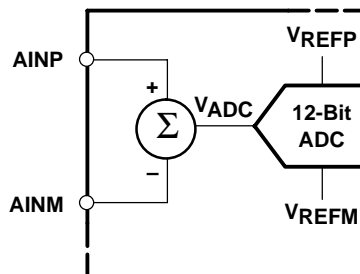


Figure 34. Differential Input Stage

In comparison to the single-ended configuration it can be seen that the voltage, V_{ADC} , which is applied at the input of the ADC, is the difference between the input AINP and AINM. The voltage V_{ADC} can be calculated as follows:

$$V_{ADC} = \text{ABS}(AINP - AINM) \quad (2)$$

An advantage to single-ended operation is that the common-mode voltage

$$V_{CM} = \frac{AINM + AINP}{2} \quad (3)$$

can be rejected in the differential configuration, if the following condition for the analog input voltages is true:

$$AGND \leq AINM, AINP \leq AV_{DD} \quad (4)$$

$$1 \text{ V} \leq V_{CM} \leq 4 \text{ V} \quad (5)$$

SINGLE-ENDED MODE OF OPERATION

The THS1209 can be configured for single-ended operation using dc or ac coupling. In every case, the input of the THS1209 should be driven from an operational amplifier that does not degrade the ADC performance. Because the THS1209 operates from a 5-V single supply, it is necessary to level-shift ground-based bipolar signals to comply with its input requirements. This can be achieved with dc- and ac-coupling.

DC COUPLING

An operational amplifier can be configured to shift the signal level according to the analog input voltage range of the THS1209. The analog input voltage range of the THS1209 goes from 1.5 V to 3.5 V. An op-amp can be used as shown in Figure 35.

Figure 35 shows an example where the analog input signal in the range from -1 V up to 1 V is shifted by an operational amplifier to the analog input range of the THS1209 (1.5 V to 3.5 V). The operational amplifier is configured as an inverting amplifier with a gain of -1 . The required dc voltage of 1.25 V at the noninverting input is derived from the 2.5 -V output reference REFOUT of the THS1209 by using a resistor divider. Therefore, the op-amp output voltage is centered at 2.5 V. The $10\ \mu\text{F}$ tantalum capacitor is required for bypassing REFOUT. REFIN of the THS1209 must be connected directly to REFOUT in single-ended mode. The use of ratio matched, thin-film resistor networks minimizes gain and offset errors.

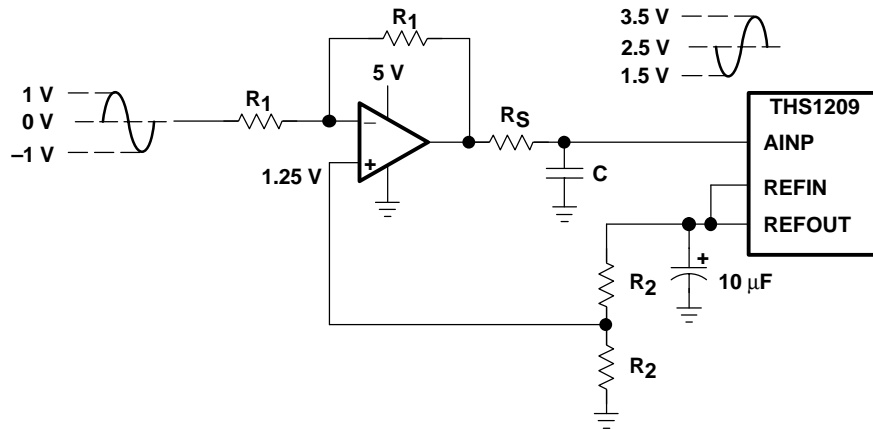


Figure 35. Level-Shift for DC-Coupled Input

DIFFERENTIAL MODE OF OPERATION

For the differential mode of operation, a conversion from single-ended to differential is required. A conversion to differential signals can be achieved by using an RF-transformer, which provides a center tap. Best performance is achieved in differential mode.

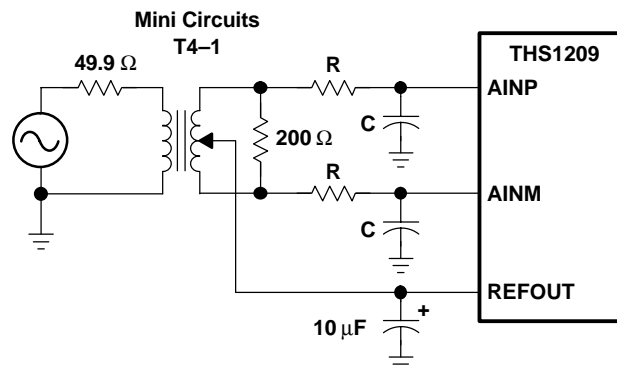


Figure 36. Transformer Coupled Input

DEFINITIONS OF SPECIFICATIONS AND TERMINOLOGY**Integral Nonlinearity**

Integral nonlinearity refers to the deviation of each individual code from a line drawn from zero through full scale. The point used as zero occurs 1/2 LSB before the first code transition. The full-scale point is defined as level 1/2 LSB beyond the last code transition. The deviation is measured from the center of each particular code to the true straight line between these two points.

Differential Nonlinearity

An ideal ADC exhibits code transitions that are exactly 1 LSB apart. DNL is the deviation from this ideal value. A differential nonlinearity error of less than ± 1 LSB ensures no missing codes.

Zero Offset

The major carry transition should occur when the analog input is at zero volts. Zero error is defined as the deviation of the actual transition from that point.

Gain Error

The first code transition should occur at an analog value 1/2 LSB above negative full scale. The last transition should occur at an analog value 1 1/2 LSB below the nominal full scale. Gain error is the deviation of the actual difference between first and last code transitions and the ideal difference between first and last code transitions.

Signal-to-Noise Ratio + Distortion (SINAD)

SINAD is the ratio of the rms value of the measured input signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for SINAD is expressed in decibels.

Effective Number of Bits (ENOB)

For a sine wave, SINAD can be expressed in terms of the number of bits. Using the following formula,

$$N = \frac{(\text{SINAD} - 1.76)}{6.02}$$

it is possible to get a measure of performance expressed as N, the effective number of bits. Thus, effective number of bits for a device for sine wave inputs at a given input frequency can be calculated directly from its measured SINAD.

Total Harmonic Distortion (THD)

THD is the ratio of the rms sum of the first six harmonic components to the rms value of the measured input signal and is expressed as a percentage or in decibels.

Spurious Free Dynamic Range (SFDR)

SFDR is the difference in dB between the rms amplitude of the input signal and the peak spurious signal.

PACKAGING INFORMATION

| Orderable Device | Status (1) | Package Type | Package Drawing | Pins | Package Qty | Eco Plan (2) | Lead finish/ Ball material (6) | MSL Peak Temp (3) | Op Temp (°C) | Device Marking (4/5) | Samples |
|------------------|---------------|--------------|-----------------|------|-------------|-----------------|--------------------------------------|----------------------|--------------|-------------------------|---------|
| THS1209IDA | ACTIVE | TSSOP | DA | 32 | 46 | RoHS & Green | NIPDAU | Level-2-260C-1 YEAR | -40 to 85 | THS1209I | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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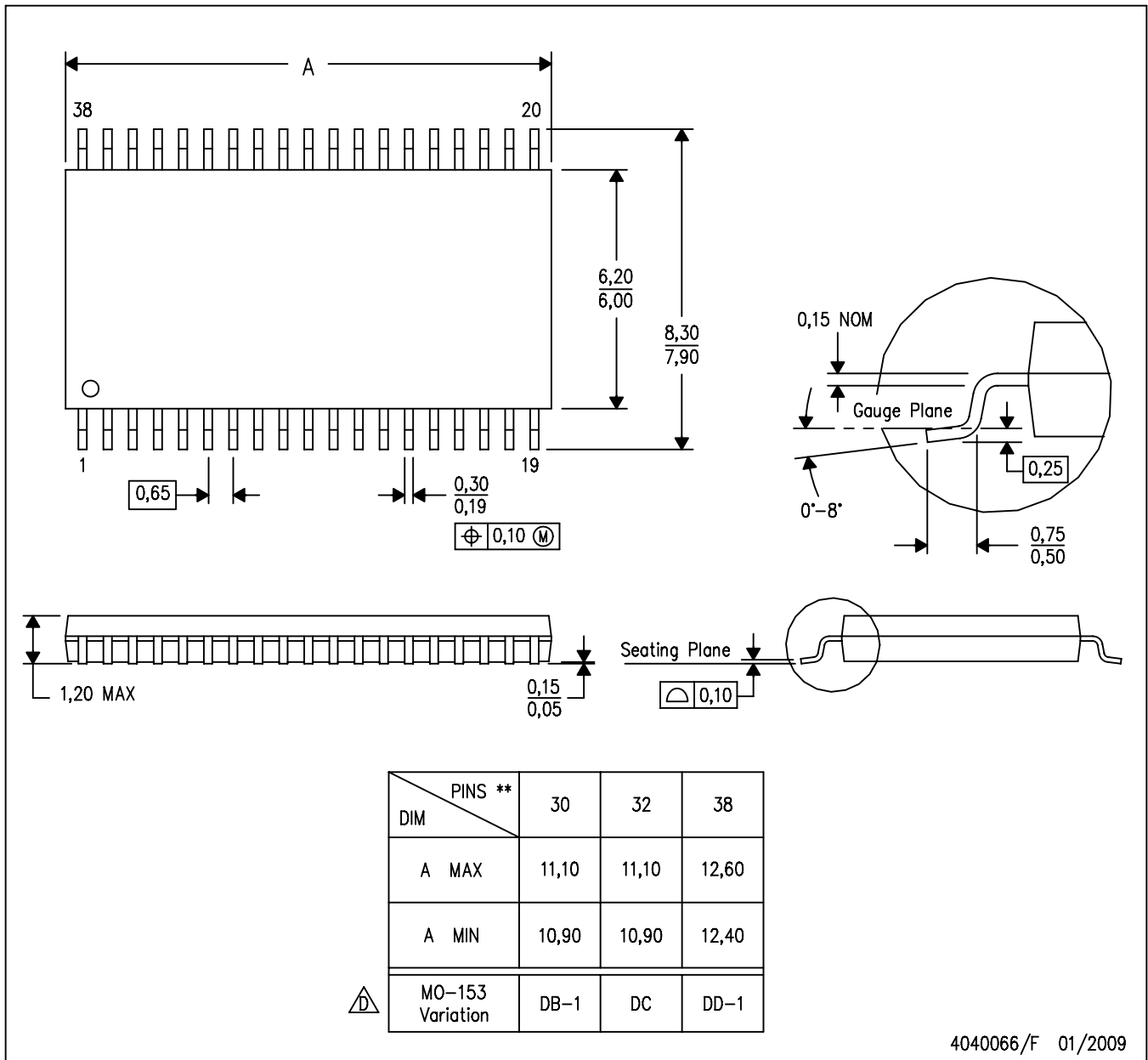
TUBE


*All dimensions are nominal

| Device | Package Name | Package Type | Pins | SPQ | L (mm) | W (mm) | T (μm) | B (mm) |
|------------|--------------|--------------|------|-----|--------|--------|--------|--------|
| THS1209IDA | DA | TSSOP | 32 | 46 | 530 | 11.89 | 3600 | 4.9 |

DA (R-PDSO-G**)
 38 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
 - Falls within JEDEC MO-153, except 30 pin body length.

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